FOR LTE, SERDES, AND WI-FI APPLICATIONS

## Your Solution for Analog / Mixed Signal / RF Testing

Looking for solutions in the highly competitive commercial market? You can rely on Johnstech to provide a cost-effective top of the line answer. Johnstech has taken all the best features found throughout the Spring Probe world and combined them into our designs.

- Suitable for BGA, LGA, QFN and WLCSP applications.
  - o Crown Tips BGA and WLCSP
  - o Spear Tips QFN and LGA
- The SHOTO and YARI product lines are designed in a singleended architecture to minimize Cres variability.
- Two test heights to provide flexibility and compliance features to accommodate both small and large packages
- · Pd alloy tips for easy cleaning
- Compatible with a floating alignment plate for accuracy

A lot of experience and care went into the design of these probes to provide our customers with the best features. Johnstech studied several hundred BGA packages to understand ball diameters and heights that are most prevalent. We were able to optimize the tip geometry based on this exhaustive study of the market.

FEATURES & BENEFITS						
FREQUENCY	≈30GHz					
PITCH	≥ 0.3mm					
TEMPERATURE	-65°C to 175°C					
CURRENT CARRY CAPABILITY @ 100%	>2.0A					
RELIABILITY	Typical Probe Life 500,000 Cycles					



All Contactors will be available for Engineering test/ Characterization with a Manual Actuator and are ready for highvolume Automated Testing.



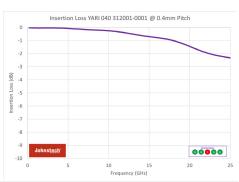


## **Electrical Specifications**

Probe Size/ Pitch (mm)	Contact Resistance* (mΩ)	CCC 100% Duty Cycle (Amps)	CCC 1% DC RMS (Amps)	1 dB Insertion Loss S <sub>21</sub> GSG (GHz)	20 dB Return Loss S <sub>11</sub> GSG (GHz)	Loop Inductance (nH)	1 dB Insertion Loss S <sub>21</sub> GSSG (GHz)	20 dB Return Loss S <sub>11</sub> GSSG (GHz)	20 dB Crosstalk S <sub>41</sub> GSSG (GHz)
0.3	70	1.63	16.30	17.9	13.5	1.14	16.7	12.6	15.5
0.4	50	1.74	17.40	17.3	11.4	1.23	20.7	8.2	16.5
0.5	40	2.26	22.60	13.5	6.8	1.08	8.6	10.6	14.1
0.8	40	2.45	24.50	16.3	7.2	1.28	15.5	11.2	13.5

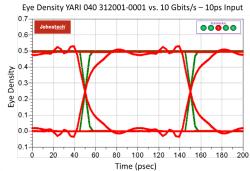
## **Mechanical Specifications**

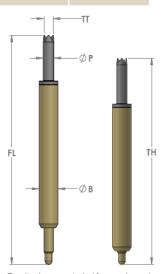
Probe Size/ Pitch (mm)	Test Height (mm)	DUT Side Compliance (mm)	Total Stroke (mm)	Force at Test Height (g)	Crown Tip-Tip TT (mm)	Uncom- pressed Length FL (mm)	Barrel Diameter B (mm)	DUT Plunger Diameter P (mm)
0.3	4.5	0.25	0.4	17	0.13	4.90	0.24	0.13
0.4	4.5	0.35	0.5	25	0.16	5.00	0.31	0.18
0.5	4.5	0.35	0.5	35	0.20	5.00	0.41	0.23
0.8	4.5	0.5	0.65	30	0.30	5.15	0.57	0.35











Results shown are typical for one size and configuration shown here. These charts are representative data. Please contact your Johnstech Sales Representative for additional specifications for specific test applications \* Contact Resistance depends on maintenance, cleaning and device materials. The values shown are measured average based on a new probe...

Johns<u>tech</u>°

Johnstech International Corporation • 1210 New Brighton Boulevard • Minneapolis, MN 55413-1641 USA Tel 612.378.2020 • Fax 612.378.2030 • www.johnstech.com • E-mail info@johnstech.com